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Weitkamp, T.[a] , Zanette, I.[b] , Schulz, G.[c] , Bech, M.[d] , Rutishauser, S.[e] , Lang, S.[c] , Donath, T.[e] , Tapfer, A.[d] , Deyhle, H.[c] , Bernard, P.[b] , Valade, J.-P.[b] , Reznikova, E.[f] , Kenntner, J.[f] , Mohr, J.[f] , Müller, B.[c] , Pfeiffer, F.[d] , David, C.[e] , Baruchel, J.[b]

X-ray grating interferometry at ESRF: Applications and recent technical developments

(2010) *AIP Conference Proceedings*, 1365, pp. 28-31.

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Abstract
We report on the implementation of X-ray grating interferometry at the imaging beamline ID19 of the European Synchrotron Radiation Facility (ESRF). We give a brief overview of the results obtained so far with this instrument and on ongoing developments. © 2011 American Institute of Physics.

Author Keywords
microtomography; Synchrotron radiation instrumentation; X-ray imaging; X-ray optics; X-ray phase contrast

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Sponsors: U.S. Department of Energy; Argonne National Laboratory; attocube systems AG; Bruker Advanced Supercon GmbH; Energetiq Technology, Inc.

Conference name: 10th International Conference on X-Ray Microscopy
Conference date: 15 August 2010 through 20 August 2010
Conference location: Chicago, IL

ISSN: 0094243X
ISBN: 9780735409255
DOI: 10.1063/1.3625297
Language of Original Document: English
Abbreviated Source Title: AIP Conf. Proc.
Document Type: Conference Paper
Source: Scopus

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